

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2438	SERIAL NO. 10701301		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT John T. Mrazic			
					FILING DATE November 3, 2003		GROUP 2815	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Applicable	
<i>AG</i>	AA	0.171.900 B1	01-2001	Sun				
	AB							
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	FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER	<i>John T. Mrazic</i>		DATE CONSIDERED	<i>4/26/04</i>				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.		
					FILING DATE PRIORITY June 22, 2000	GROUP PRIORITY 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AC	AA	5,032,545	07-1991	Doan et al.			
	AB	5,436,481	07-1995	Egawa et al.			
	AC	5,378,645	01-1995	Inoue et al.			
	AD	5,258,333	11-1993	Shappir et al.			
	AE	5,518,946	05-1996	Kuroda			
	AF	5,445,999	08-1995	Thakur et al.			
	AG	5,382,533	01-1995	Ahmad et al.			
	AH	5,663,077	09-1997	Adachi et al.			
	AI	5,026,574	06-1991	Economu et al.			
	AJ	5,612,558	03-1997	Harshfield			
	AK	5,719,083	02-1998	Komatsu			
	AL	5,760,475	06-1998	Cronin			
	FOREIGN PATENT DOCUMENTS						
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AC	AM	WO 96/39713	12-1996	PCT			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AC	AR		Wolf, S., "Silicon Processing for the VLSI Era", Lattice Press 1990, Vol. 2, pp. 212-213.				
	AS		Wolf, S., "Silicon Processing for the VLSI Era", Lattice Press 1990, Vol. 2, pp. 188-189, 194-195, 609-614.				
AC	AT		Ko, L. et al., "The Effect of Nitrogen Incorporation into the Gate Oxide by Using Shallow Implantation of Nitrogen and Drive-In Process", IEEE 1996, pp. 32-35.				
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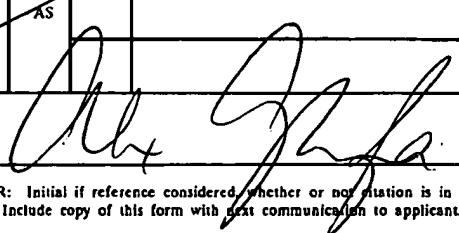
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
AC	AA	5,834,372	11-1998	Lee				
	AB	5,619,057	04-1997	Komatsu				
	AC	5,633,036	05-1997	Seebauer et al.				
	AD	6,054,396	04-2000	Doan				
	AE	6,174,821	01-2001	Doan				
	AF	5,939,750	08-1999	Early				
	AG	5,254,489	10-1993	Nakata				
	AH	5,464,792	11-1995	Tseng et al.				
	AI	5,620,908	04-1997	Inoh et al.				
	AJ	5,716,864	02-1998	Abe				
	AK	5,972,783	10-1999	Arai et al.				
	AL	6,093,661	07-2000	Trivedi et al.				
FOREIGN PATENT DOCUMENTS								
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AC	AR	Doyle, B. et al., "Simultaneous Growth of Different Thickness Gate Oxides in Silicon CMOS Processing", IEEE Vol. 16 (7), July 1995, pp. 301-302.						
AC	AS	Kuroi, T. et al., "The Effects of Nitrogen Implantation Into P+Poly-Silicon Gate on Gate Oxide Properties", 1994 Sympos. on VLSI Technology Digest of Technical Papers, IEEE 1994, pp. 107-108.						
AC	AT	Liu, C.T. et al., "Multiple Gate Oxide Thickness for 2GHz System-on-a-Chip Technologies", IEEE 1998, pp. 589-592.						
EXAMINER		<i>John J. [Signature]</i>			DATE CONSIDERED <i>4/26/04</i>			
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*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
Al	AA	5,994,749	11-1999	Oda				
	AB	5,674,788	10-1997	Wristers et al.				
	AC	5,596,218	01-1997	Soleimani et al.				
	AD	5,960,302	09-1999	Ma et al.				
	AE	6,207,532 B1	03-2001	Lio et al.				
	AF	6,114,203	09-2000	Ghidini et al.				
	AG	6,110,842	08-2000	Okuno et al.				
	AH	6,091,110	07-2000	Hebert et al.				
	AI	5,330,920	07-1994	Soleimani et al.				
	AJ	6,140,187	10-2000	DeBusk et al.				
	AK	6,197,701	03-2001	Shue et al.				
	Xe	AL	6,091,109	07-2000	Hasegawa			
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Ac	AA	6,080,682	06-2000	Ibok				
	AB	5,685,949	11-1997	Yashima				
	AC	6,268,296 B1	07-2001	Misium et al.				
	AD	6,232,244 B1	05-2001	Ibok				
	AE	6,255,703 B1	07-2001	Hause et al.				
	AF	6,274,442 B1	08-2001	Gardner et al.				
	AG	6,228,701 B1	05-2001	Dehm et al.				
	AH	6,136,636	10-2000	Wu				
	AI	6,033,998	03-2000	Aronowitz et al.				
	AJ	6,057,220	05-2000	Ajmera et al.				
	AK	6,087,229	07-2000	Aronowitz et al.				
	AL	5,998,253	12-1999	Loh et al.				
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
AL	AA	5,763,922	06-1998	Chau				
	AB	6,225,167 B1	05-2001	Yu et al.				
	AC	5,960,289	09-1999	Tsul et al.				
	AD	5,972,800	10-1999	Hasegawa				
	AE	6,146,948	11-2000	Wu et al.				
	AF	6,362,085	03-2002	Yu et al.				
	AG	5,164,331	11-1992	Lin et al.				
	AH	5,318,924	06-1994	Lin et al.				
	AI	5,449,631	09-1995	Giewont et al.				
	AJ	5,518,958	05-1996	Giewont et al.				
AL	AK	6,201,303	03-2001	Ngo et al.				
	AL	6,399,445	06-2002	Hattangady et al.				
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AC	AA	6,331,492 B2	12-2001	Misium et al.					
	AB	6,080,629	06-2000	Gardner et al.					
	AC	5,970,345	10-1999	Hattangady et al.					
	AD	5,885,877	03-1999	Gardner et al.					
	AE	6,323,114 B1	11-2001	Hattangady et al.					
	AF	6,184,110 B1	02-2001	Ono et al.					
	AG	5,837,598	11-1998	Aronowitz et al.					
	AH	6,450,116	09-2002	Noble et al.					
	AI	4,605,447	08-1986	Brotherton et al.					
	AJ	6,207,586	03-2001	Ma et al.					
	AC	AK	5,837,592	11-1998	Chang et al.				
		AL	5,334,554	08-1994	Lin et al.				
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AG	AA	6,297,162	10-2001	Jang et al.				
	AB	6,436,771 B1	08-2002	Jang et al.				
	AC	6,413,881	07-2002	Aronowitz et al.				
	AD	6,110,780	08-2000	Yu et al.				
	AE	5,861,651	01-1999	Brasen et al.				
	AF	5,840,610	11-1998	Gilmer et al.				
	AG	5,500,380	03-1996	Kim				
	AH	6,410,991 B1	06-2002	Kawai et al.				
	AI	6,482,690 B2	11-2002	Shibata				
	AJ	6,492,690 B2	12-2002	Ueno et al.				
AG	AK	6,399,448	06-2002	Mukhopadhyay +				
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